Technical Data

Flatness:	0.1µm
Parallelism:	0.2µm
Diameter:	30mm

Parallelism Check of Measuring Faces by Means of Interference Fringe Produced by an Optical Parallel

The parallelism of the measuring faces can be determined as follows: wring the optical parallel to the anvil and observe the number of interference fringes produced on the spindle face under normal measuring force.

The diagram below shows parallelism of about $1\mu m$ (0.32 $\mu m \times 3 = 0.96\mu m$).

There should not be more than one fringe visible on the anvil face.

The four parallels are sized such that testing can be performed at each quarter revolution of the spindle.





Flatness Check of Measuring Faces Using Interference Fringe Pattern Produced by an Optical Flat





Optical Parallels

SERIES 157

FEATURES

- Designed to inspect parallelism and flatness of measuring faces of micrometers.
- Each set consists of 4 sizes.
- Supplied in fitted carrying case.



SPECIFICATIONS

Metric

Range of micrometer to be checked	Order No.	Sizes of parallels included in set
0-25mm	157-903	12.00, 12.12, 12.25, 12.37mm
25-50mm	157-904	25.00, 25.12, 25.25, 25.37mm

Inch		
Range of micrometer to be checked	Order No.	Sizes of parallels included in set
0-1 "	157-901	.5000", .5062", .5125", .5187"
1-2"	157-902	1.0000", 1.0062", 1.0125", 1.0187"

Optical Flats SERIES 158

FEATURES

SPECIFICATIONS

Order No.

158-117

158-119

158-118

158-120

Metric Flatness grade

0.2µm

0.1µm

- Of circular form with one surface accurately polished, used for inspecting the flatness of gauge block or platen reference surfaces, micrometer measuring faces or any other very flat surface of high reflectivity.
- Available in two sizes and two grades of flatness tolerance for the specified surface.



Diameter/Thickness

45mm/12mm

60mm/15mm

45mm/12mm

60mm/15mm

158-118

Mitutoyo

Inch		
Flatness grade	Order No.	Diameter/Thickness
.000004 "	158-122	1.8"/.5"
	158-124	2.4"/.6"